

Notice of References Cited	Application/Control No. 10/724,193	Applicant(s)/Patent Under Reexamination SUNTER, STEPHEN K.	
	Examiner Toan M. Le	Art Unit 2863	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,211,803	04-2001	Sunter, Stephen Kenneth	341/120
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Acevedo et al., VDDQ: A Built-In Self-Test Scheme for Analog On-Chip Diagnosis Compliant with the IEEE 1149.4 Mixed-Signal Test Bus Standard, 2002 IEEE
	V	Sunter et al., BIST for Phase-Locked Loops in Digital Applications, 1999 IEEE, Pages 532-540
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.